



Date:- 4 Feb 2002

Data Sheet Issue:- 3

## Phase Control Thyristor

### Type SKT552/16E

#### Absolute Maximum Ratings

#### VOLTAGE RATINGS

Symbol	Parameter	MAXIMUM	UNITS
$V_{DRM}$	Repetitive peak off-state voltage, (note 1)	1600	V
$V_{DSM}$	Non-repetitive peak off-state voltage, (note 1)	1600	V
$V_{RRM}$	Repetitive peak reverse voltage, (note 1)	1600	V
$V_{RSM}$	Non-repetitive peak reverse voltage, (note 1)	1700	V

#### OTHER RATINGS

Symbol	Parameter	MAXIMUM	UNITS
$I_{T(AV)}$	Mean on-state current. $T_{sink}=55^{\circ}C$ , (note 2)	734	A
$I_{T(AV)}$	Mean on-state current. $T_{sink}=85^{\circ}C$ , (note 2)	494	A
$I_{T(AV)}$	Mean on-state current. $T_{sink}=85^{\circ}C$ , (note 3)	290	A
$I_{T(RMS)}$	Nominal RMS on-state current. $T_{sink}=25^{\circ}C$ , (note 2)	1465	A
$I_{T(d.c.)}$	D.C. on-state current. $T_{sink}=25^{\circ}C$ , (note 4)	1231	A
$I_{TSM}$	Peak non-repetitive surge $t_p=10ms$ , $V_{rm}=V_{RRM}$ , (note 5)	7700	A
$I_{TSM2}$	Peak non-repetitive surge $t_p=10ms$ , $V_{rm}\leq 10V$ , (note 5)	9240	A
$I^2t$	$I^2t$ capacity for fusing $t_p=10ms$ , $V_{rm}=V_{RRM}$ , (note 5)	$296\times 10^3$	$A^2s$
$I^2t$	$I^2t$ capacity for fusing $t_p=10ms$ , $V_{rm}\leq 10V$ , (note 5)	$427\times 10^3$	$A^2s$
$dI_T/dt$	Maximum rate of rise of on-state current (repetitive), (Note 6)	500	$A/\mu s$
	Maximum rate of rise of on-state current (non-repetitive), (Note 6)	1000	$A/\mu s$
$V_{RGM}$	Peak reverse gate voltage	5	V
$P_{G(AV)}$	Mean forward gate power	2	W
$P_{GM}$	Peak forward gate power	30	W
$V_{GD}$	Non-trigger gate voltage, (Note 7)	0.25	V
$T_{HS}$	Operating temperature range	-40 to +125	$^{\circ}C$
$T_{stg}$	Storage temperature range	-40 to +150	$^{\circ}C$

Notes: -

- 1) De-rating factor of 0.13% per  $^{\circ}C$  is applicable for  $T_j$  below  $25^{\circ}C$ .
- 2) Double side cooled, single phase; 50Hz,  $180^{\circ}$  half-sinewave.
- 3) Single side cooled, single phase; 50Hz,  $180^{\circ}$  half-sinewave.
- 4) Double side cooled.
- 5) Half-sinewave,  $125^{\circ}C T_j$  initial.
- 6)  $V_D=67\% V_{DRM}$ ,  $I_{TM}=500A$ ,  $I_{FG}=1A$ ,  $t_i\leq 0.5\mu s$ ,  $T_{case}=125^{\circ}C$ .
- 7) Rated  $V_{DRM}$ .

Characteristics

Symbol	PARAMETER	MIN.	TYP.	MAX.	TEST CONDITIONS (Note 1)	UNITS
V <sub>TM</sub>	Maximum peak on-state voltage	-	-	1.78	I <sub>TM</sub> =1550A	V
V <sub>0</sub>	Threshold voltage	-	-	1.03		V
r <sub>S</sub>	Slope resistance	-	-	0.483		mΩ
dV/dt	Critical rate of rise of off-state voltage	1000	-	-	V <sub>D</sub> =80% V <sub>DRM</sub> , linear ramp, gate o/c	V/μs
I <sub>DRM</sub>	Peak off-state current	-	-	40	Rated V <sub>DRM</sub>	mA
I <sub>RRM</sub>	Peak reverse current	-	-	40	Rated V <sub>RRM</sub>	mA
V <sub>GT</sub>	Gate trigger voltage	-	-	3.0	T <sub>j</sub> =25°C, V <sub>D</sub> =10V, I <sub>T</sub> =2A	V
I <sub>GT</sub>	Gate trigger current	-	-	150		mA
I <sub>H</sub>	Holding current	-	-	500	T <sub>j</sub> =25°C	mA
t <sub>gd</sub>	Gate controlled turn-on delay time	-	0.5	1.0	V <sub>D</sub> =80% V <sub>DRM</sub> , I <sub>TM</sub> =1000A, di/dt=10A/μs, I <sub>FG</sub> =2A, t <sub>r</sub> =0.5μs, T <sub>j</sub> =25°C	μs
t <sub>gt</sub>	Turn-on time	-	1.0	2.0		
Q <sub>rr</sub>	Recovered Charge	-	750	-	I <sub>TM</sub> =1000A, t <sub>p</sub> =1000μs, di/dt=10A/μs, V <sub>r</sub> =50V	μC
Q <sub>ra</sub>	Recovered Charge, 50% chord	-	600	690		μC
I <sub>rm</sub>	Reverse recovery current	-	70	-		A
t <sub>rr</sub>	Reverse recovery time, 50% chord	-	12	-		μs
t <sub>q</sub>	Turn-off time	-	160	-	I <sub>TM</sub> =1000A, t <sub>p</sub> =1000μs, di/dt=10A/μs, V <sub>r</sub> =50V, V <sub>dr</sub> =80% V <sub>DRM</sub> , dV <sub>dr</sub> /dt=20V/μs	μs
		-	250	-	I <sub>TM</sub> =1000A, t <sub>p</sub> =1000μs, di/dt=10A/μs, V <sub>r</sub> =50V, V <sub>dr</sub> =80% V <sub>DRM</sub> , dV <sub>dr</sub> /dt=200V/μs	
R <sub>th(j-hs)</sub>	Thermal resistance, junction to heatsink	-	-	0.05	Double side cooled	K/W
		-	-	0.1	Single side cooled	K/W
F	Mounting force	5.3	-	10		kN
W <sub>t</sub>	Weight	-	90	-		g

Notes: -

1) Unless otherwise indicated T<sub>j</sub>=125°C.

**Notes on Ratings and Characteristics****1.0 Voltage Grade Table**

Voltage Grade	V <sub>DRM</sub> V V <sub>DSM</sub>	V <sub>RRM</sub>	V <sub>RSM</sub> V	V <sub>D</sub> DC V	V <sub>R</sub>
16	1600		1700		1040

**2.0 Extension of Voltage Grades**

This report is applicable to other and higher voltage grades when supply has been agreed by Sales/Production.

**3.0 De-rating Factor**

A blocking voltage de-rating factor of 0.13%/°C is applicable to this device for T<sub>j</sub> below 25°C.

**4.0 Repetitive dv/dt**

Standard dv/dt is 1000V/μs.

**5.0 Rate of rise of on-state current**

The maximum un-primed rate of rise of on-state current must not exceed 1000A/μs at any time during turn-on on a non-repetitive basis. For repetitive performance, the on-state rate of rise of current must not exceed 500A/μs at any time during turn-on. Note that these values of rate of rise of current apply to the total device current including that from any local snubber network.

**6.0 Gate Drive**

The recommended pulse gate drive is 30V, 30Ω with a short-circuit current rise time of not more than 0.5μs. This gate drive must be applied when using the full di/dt capability of the device.

The pulse duration may need to be configured according to the application but should be no shorter than 20μs, otherwise an increase in pulse current may be needed to supply the necessary charge to trigger.

**7.0 Computer Modelling Parameters****7.1 Device Dissipation Calculations**

$$I_{AV} = \frac{-V_0 + \sqrt{V_0^2 + 4 \cdot ff \cdot r_s \cdot W_{AV}}}{2 \cdot ff \cdot r_s} \quad \text{and:} \quad W_{AV} = \frac{\Delta T}{R_{th}}$$

$$\Delta T = T_{j\max} - T_{Hs}$$

Where V<sub>0</sub>=1.03V, r<sub>s</sub>=0.483mΩ

R<sub>th</sub> = Supplementary thermal impedance, see table below.

ff = Form factor, see table below.

Supplementary Thermal Impedance						
Conduction Angle	30°	60°	90°	120°	180°	270°
Square wave Double Side Cooled	0.071	0.069	0.065	0.061	0.057	0.053
Square wave Single Side Cooled	0.12	0.119	0.115	0.111	0.107	0.103
Sine wave Double Side Cooled	0.053	0.052	0.0516	0.0513	0.0505	
Sine wave Single Side Cooled	0.103	0.102	0.1017	0.1013	0.1005	

Form Factors						
Conduction Angle	30°	60°	90°	120°	180°	270°
Square wave	3.46	2.45	2	1.73	1.41	1.15
Sine wave	3.98	2.78	2.22	1.88	1.57	1

## 7.2 Calculating $V_T$ using ABCD Coefficients

The on-state characteristic  $I_T$  vs.  $V_T$ , on page 5 is represented in two ways;

- (i) the well established  $V_0$  and  $r_s$  tangent used for rating purposes and
- (ii) a set of constants A, B, C, D, forming the coefficients of the representative equation for  $V_T$  in terms of  $I_T$  given below:

$$V_T = A + B \cdot \ln(I_T) + C \cdot I_T + D \cdot \sqrt{I_T}$$

The constants, derived by curve fitting software, are given below for both hot and cold characteristics. The resulting values for  $V_T$  agree with the true device characteristic over a current range, which is limited to that plotted.

25°C Coefficients		125°C Coefficients	
A	0.608472	A	0.255645
B	0.1136108	B	0.1512629
C	$4.010517 \times 10^{-4}$	C	$5.081796 \times 10^{-4}$
D	$-8.037156 \times 10^{-3}$	D	$-9.373878 \times 10^{-3}$

## 7.3 D.C. Thermal Impedance Calculation

$$r_t = \sum_{p=1}^{p=n} r_p \cdot \left( 1 - e^{\frac{-t}{\tau_p}} \right)$$

Where  $p = 1$  to  $n$ ,  $n$  is the number of terms in the series and:

$t$  = Duration of heating pulse in seconds.

$r_t$  = Thermal resistance at time  $t$ .

$r_p$  = Amplitude of  $r_{th}$  term.

$\tau_p$  = Time Constant of  $r_{th}$  term.

D.C. Double Side Cooled				
Term	1	2	3	4
$r_p$	0.12000552	0.01609235	$8.812673 \times 10^{-3}$	$3.659765 \times 10^{-3}$
$\tau_p$	0.3391689	0.09405764	0.12195269	$2.169197 \times 10^{-3}$

D.C. Single Side Cooled					
Term	1	2	3	4	
$r_p$	0.06157697	$8.431182 \times 10^{-3}$	0.01031315	0.01613806	$5.181088 \times 10^{-3}$
$\tau_p$	2.136132	1.212898	0.1512408	0.04244	$2.889595 \times 10^{-3}$

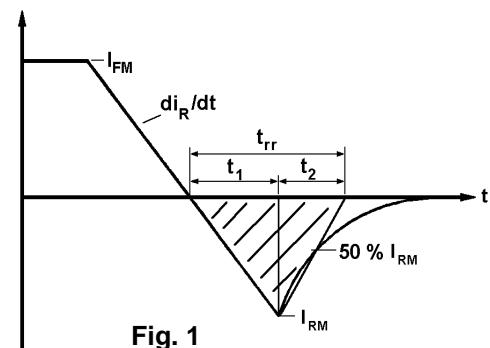
## 8.0 Reverse recovery ratings

(i)  $Q_{ra}$  is based on 50%  $I_{rm}$  chord as shown in Fig. 1.

(ii)  $Q_{rr}$  is based on a 150μs integration time.

i.e. 
$$Q_{rr} = \int_0^{150\mu s} i_{rr} dt$$

(iii) 
$$K \text{ Factor} = \frac{t_1}{t_2}$$



Curves

Figure 1 - On-state characteristics of Limit device

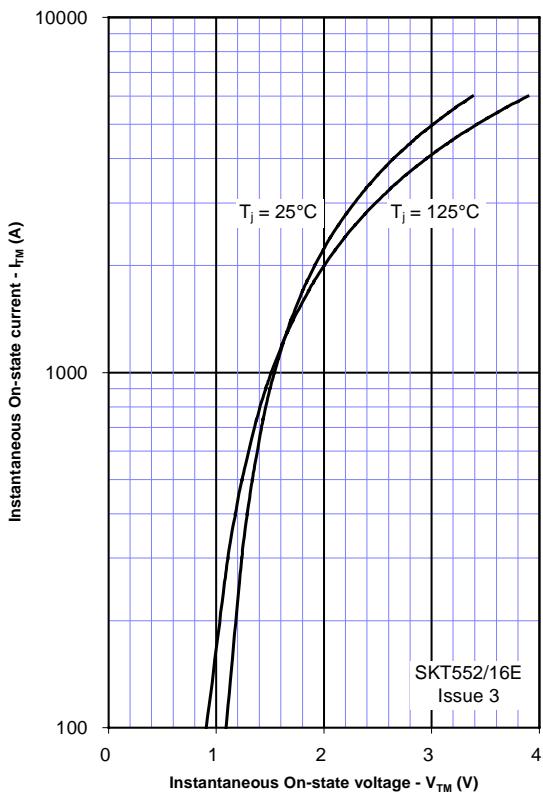


Figure 2 - Transient Thermal Impedance

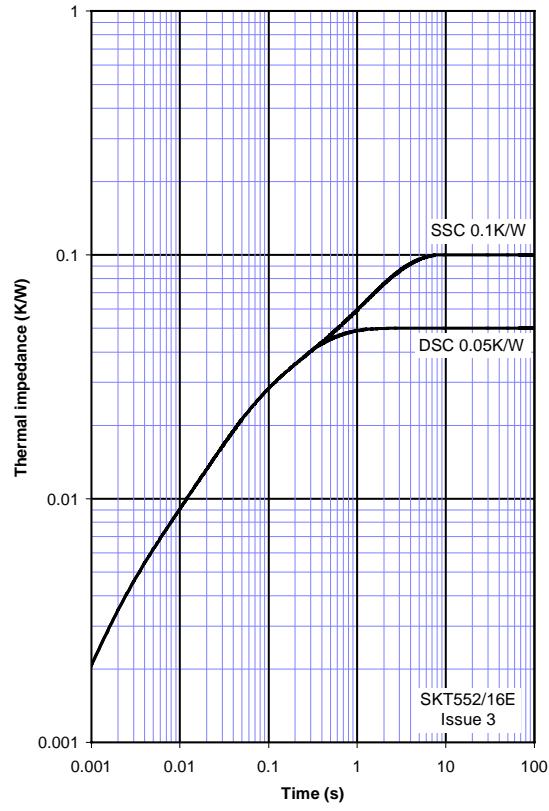


Figure 3 - Gate Characteristics – Trigger Limits

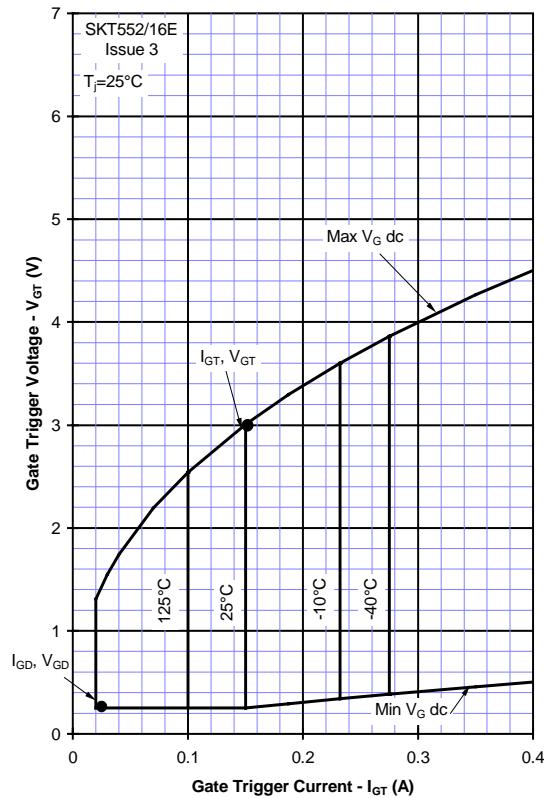


Figure 4 - Gate Characteristics - Power Curves

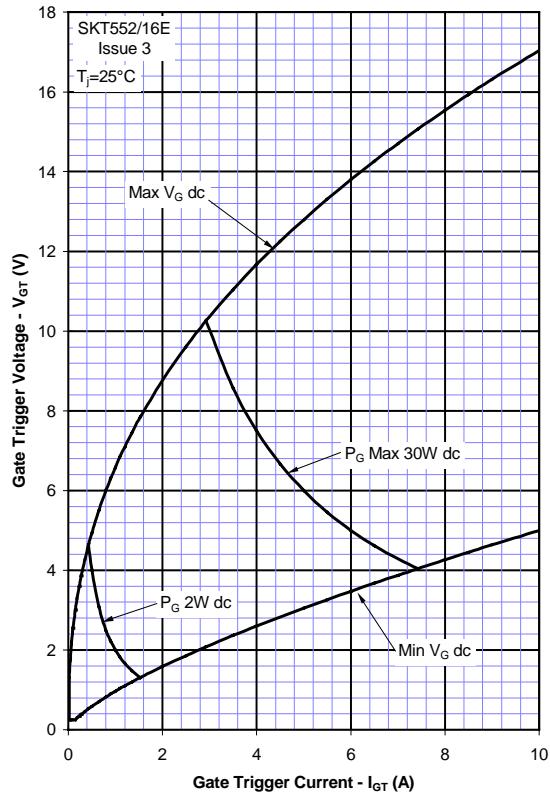


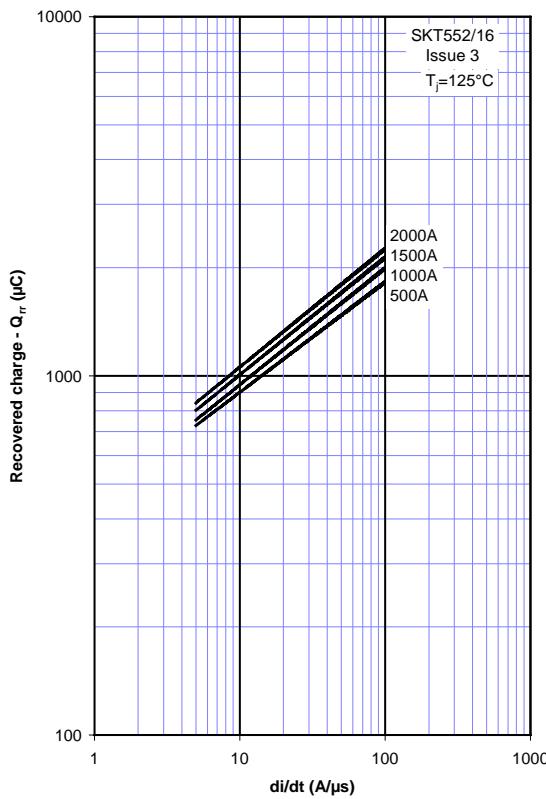
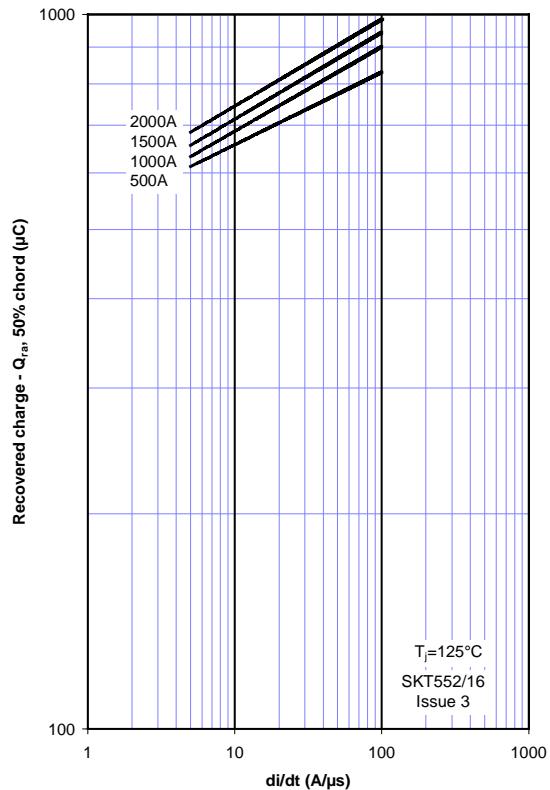
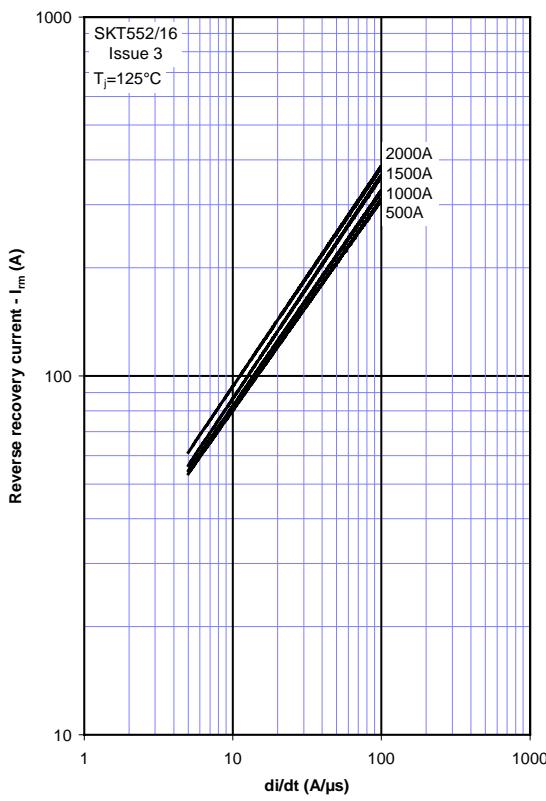
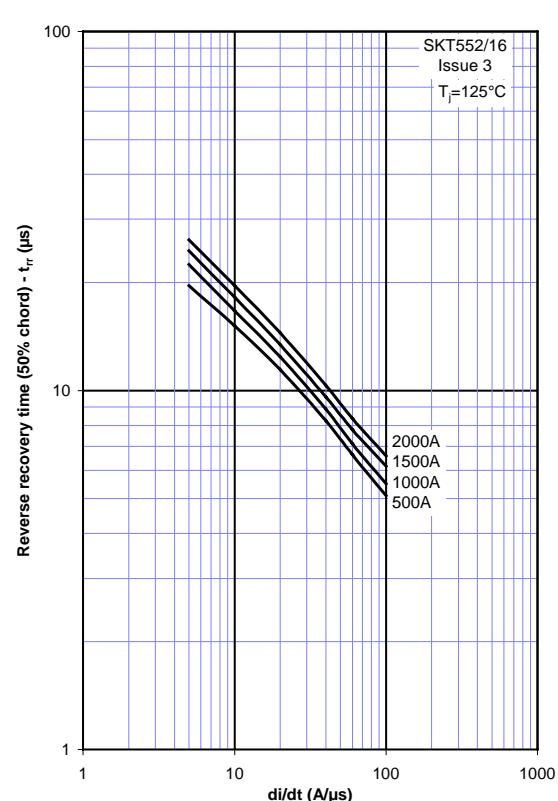
Figure 5 – Recovered Charge,  $Q_{rr}$ Figure 6 – Recovered charge,  $Q_{ra}$  (50% chord)Figure 7 – Reverse recovery current,  $I_{rm}$ Figure 8 – Reverse recovery time,  $t_{rr}$  (50% chord)

Figure 9 – On-state current vs. Power dissipation – Double Side Cooled (Sine wave)

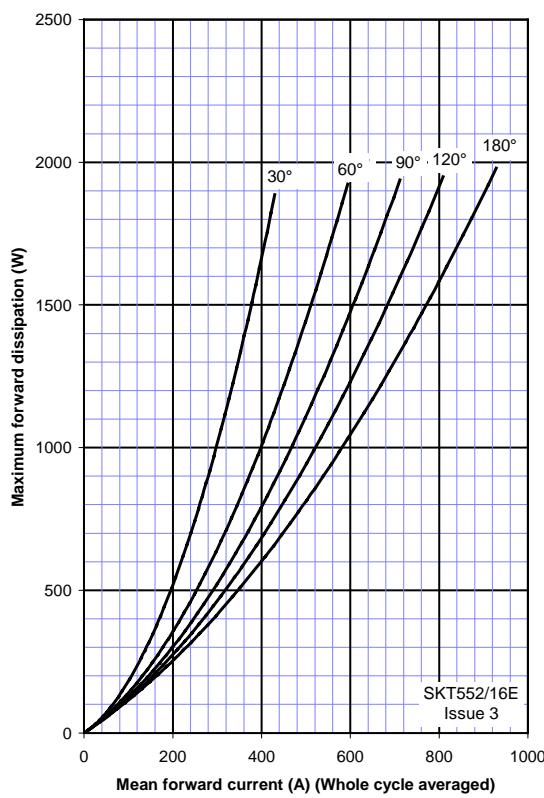


Figure 10 – On-state current vs. Heatsink temperature - Double Side Cooled (Sine wave)

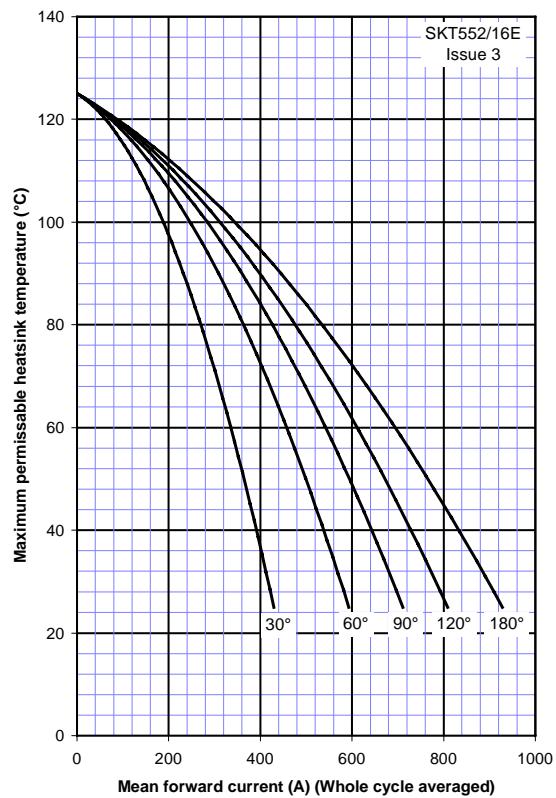


Figure 11 – On-state current vs. Power dissipation – Double Side Cooled (Square wave)

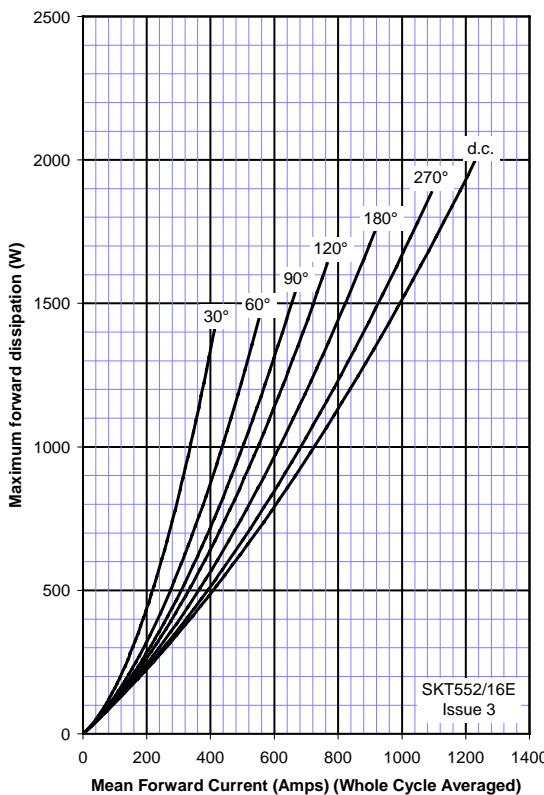


Figure 12 – On-state current vs. Heatsink temperature - Double Side Cooled (Square wave)

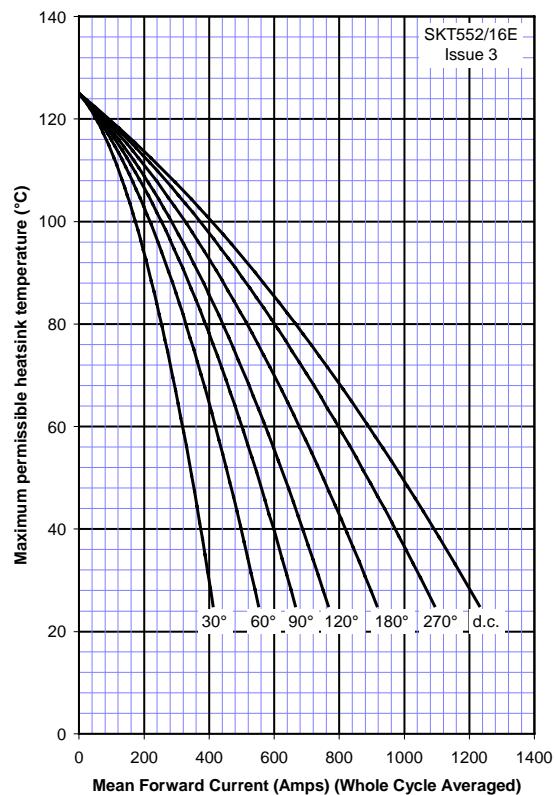


Figure 13 – On-state current vs. Power dissipation –  
Single Side Cooled (Sine wave)

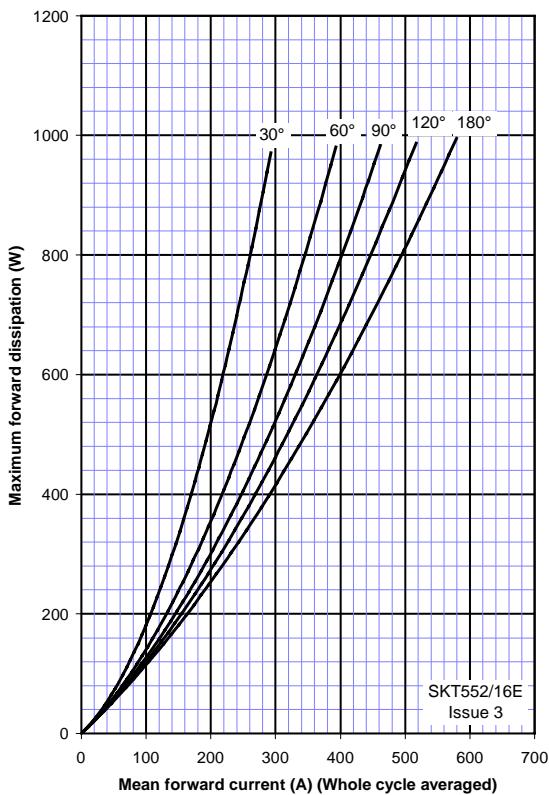


Figure 15 – On-state current vs. Power dissipation –  
Single Side Cooled (Square wave)

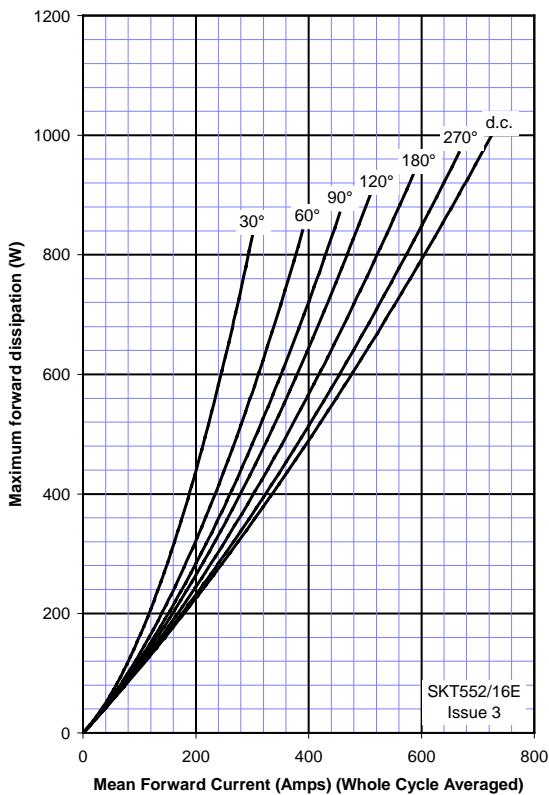


Figure 14 – On-state current vs. Heatsink temperature -  
Single Side Cooled (Sine wave)

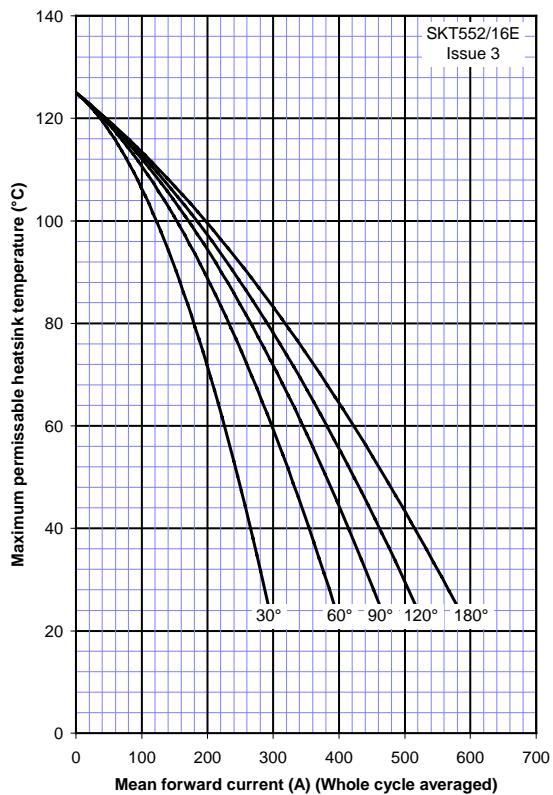


Figure 16 – On-state current vs. Heatsink temperature -  
Single Side Cooled (Square wave)

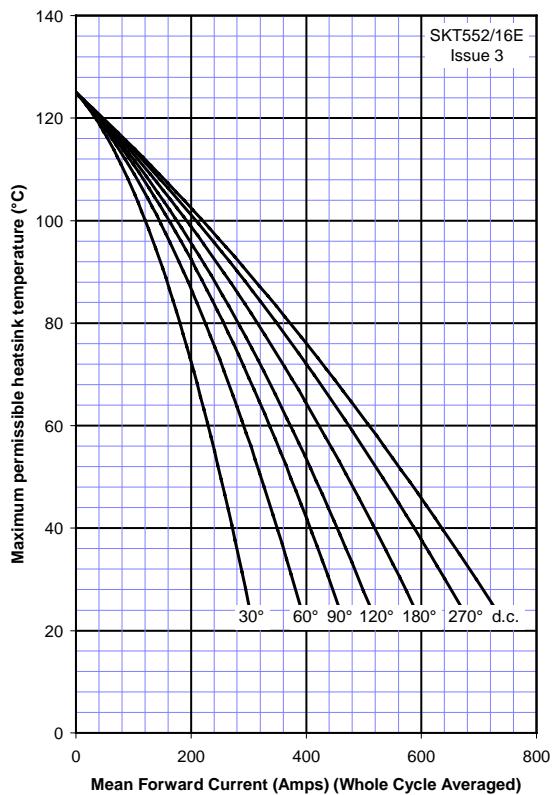
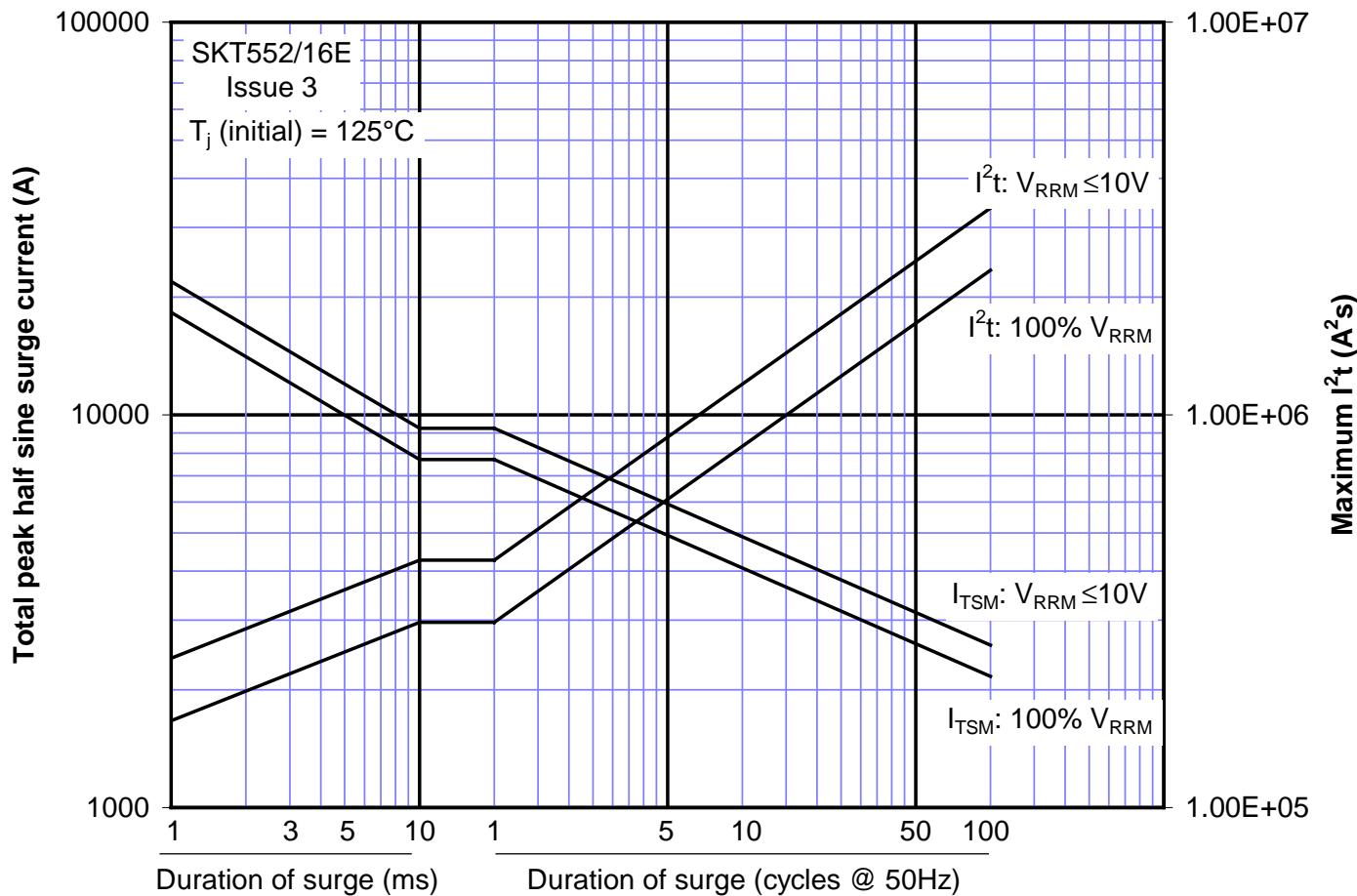


Figure 17 – Maximum surge and  $I^2t$  Ratings

Outline Drawing & Ordering Information